

2018



THE ONLY RESOURCE DEDICATED  
TO ELECTRONIC TEST ENGINEERING

## HOW TO REACH TO TEST ENGINEERS

**When asked about EE, here are some of the results from the recent 2018 Subscriber Profile Survey:**

- ▶ **79%** read 3 out of 4 issues
- ▶ **94%** of EE subscribers are involved in purchasing decisions
- ▶ The average EE subscriber has received EE for **8.3** years
- ▶ **86,250** receive EE with pass-along
- ▶ **61%** state they would be more likely to consider a product after seeing an ad in EE
- ▶ **68%** have visited the EE website after reading EE
- ▶ **82%** state print magazines influence their purchasing decision - the #1 response!

**Now is the best time to reach the test engineering market ... with a print or electronic ad in EE. Call to reserve your space in December!**

### DECEMBER EDITORIAL PREVIEW

#### Special Report: OSCILLOSCOPES

Touchscreen display, convergence, and smart features driving latest trends

#### Special Report: 5G

See which innovations will move the needle in 2019 as 5G New Radio becomes the standard

#### INSTRUMENTATION

A game-changer in AFGs

#### CYBERSECURITY

How virtual applications reduce attack surface for test program sets

#### Product Focus: RFICs

Growth of wireless electronics spurs interest in RFICs

#### 3D PRINTING

3D printing puts R&D into warp-speed mode

**SPACE DEADLINE: Nov 1    MATERIALS DUE: Nov 6**



### PLAN AHEAD!

**THE NEW 2019  
EDITORIAL  
CALENDAR  
IS HERE:**

[Editorial Calendar](#)



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